



US Patent & Trademark Office

[Subscribe \(Full Service\)](#) [Register \(Limited Service, Free\)](#) [Login](#)Search: ☒ The ACM Digital Library ☐ The Guide**SEARCH**

Nothing Found

Your search for **+coverability +inflator** did not return any results.

You may want to try an [Advanced Search](#) for additional options.

Please review the [Quick Tips](#) below or for more information see the [Search Tips](#).

Quick Tips

- Enter your search terms in lower case with a space between the terms.

sales offices

You can also enter a full question or concept in plain language.

Where are the sales offices?

- Capitalize proper nouns to search for specific people, places, or products.

John Colter, Netscape Navigator

- Enclose a phrase in double quotes to search for that exact phrase.

"museum of natural history" "museum of modern art"

- Narrow your searches by using a **+** if a search term must appear on a page.

museum +art

- Exclude pages by using a **-** if a search term must not appear on a page.

museum -Paris

Combine these techniques to create a specific search query. The better your description of the information you want, the more relevant your results will be.

museum +"natural history" dinosaur -Chicago

The ACM Portal is published by the Association for Computing Machinery. Copyright © 2005 ACM, Inc.

[Terms of Usage](#) [Privacy Policy](#) [Code of Ethics](#) [Contact Us](#)


[Subscribe \(Full Service\)](#) [Register \(Limited Service, Free\)](#) [Login](#)

 Search: ☒ The ACM Digital Library ☐ The Guide

THE ACM DIGITAL LIBRARY


[Feedback](#) [Report a problem](#) [Satisfaction survey](#)

 Terms used **coverability inflator**

Found 15 of 154,226

Sort results by

Display results


[Save results to a Binder](#)

[Search Tips](#)
☐ Open results in a new window

[Try an Advanced Search](#)
[Try this search in The ACM Guide](#)

Results 1 - 15 of 15

 Relevance scale ☐ ☐ ☐ ☐ ☐

1 [Solving coverability problems of petri nets by partial deduction](#)

Michael Leuschel, Helko Lehmann

 September 2000 **Proceedings of the 2nd ACM SIGPLAN international conference on Principles and practice of declarative programming**

 Full text available: [pdf\(562.25 KB\)](#) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

Keywords: abstract interpretation, concurrency, logic programming, model checking, partial evaluation, petri nets, program analysis and verification

2 [The complexity of the equivalence problem for commutative semigroups and symmetric vector addition systems](#)

D T Huynh

 December 1985 **Proceedings of the seventeenth annual ACM symposium on Theory of computing**

 Full text available: [pdf\(799.41 KB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

This paper shows that the equivalence problems for commutative semigroups and symmetric vector addition systems are decidable in space $cN \log N$ for some fixed constant c , solving an open question by Cardoza, Lipton, Mayr, and Meyer. From the exponential-space completeness of the word problems, it follows that our upper bound is nearly optimal.

3 [Petri-net evaluation using APL2](#)

Robert G. Willhoft

 July 1992 **ACM SIGAPL APL Quote Quad , Proceedings of the international conference on APL**, Volume 23 Issue 1

 Full text available: [pdf\(1.17 MB\)](#) Additional Information: [full citation](#), [abstract](#), [references](#), [index terms](#)

A Petri net is a graphical and mathematical modeling tool useful in the analysis of concurrent, asynchronous, distributed, parallel, nondeterministic, and/or stochastic systems. In addition, interest in Petri nets is increasing in the software community to model the behavior of parallel computer programs. The introduction of timed Petri nets allows system or program performance to be estimated as well. This paper begins with a general discussion, including definitions, for both o ...

4 [Compositional verification of concurrent systems using Petri-net-based condensation](#)

[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [Alerts](#) |

Welcome United States Patent and Trademark Office

[Search Results](#)[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "((coverability inflator)<in>metadata)"

Your search matched 0 of 1152881 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by **Relevance** in **Descending** order. [e-mail](#)[» View Session History](#)[» New Search](#)[» Key](#)IEEE JNL IEEE Journal or
MagazineIEE JNL IEE Journal or
MagazineIEEE IEEE Conference
CNF ProceedingIEE CNF IEE Conference
ProceedingIEEE IEEE Standard
STD

Modify Search

☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract**No results were found.**

Please edit your search criteria and try again. Refer to the Help pages if you need assistance revisir

Indexed by
 Inspec[Help](#) [Contact Us](#) [Privacy & :](#)

© Copyright 2005 IEEE –



US Patent & Trademark Office

[Subscribe \(Full Service\)](#) [Register \(Limited Service, Free\)](#) [Login](#)

Search: ☐ The ACM Digital Library ☒ The Guide

coverage symbolic

SEARCH

THE GUIDE TO COMPUTING LITERATURE



[Feedback](#) [Report a problem](#) [Satisfaction survey](#)

Terms used **coverage symbolic**

Found **21,405** of **863,039**

Sort results
by

relevance ☒

Display
results

expanded form ☒

[Save results to a Binder](#)

[Search Tips](#)

☐ Open results in a new
window

[Try an Advanced Search](#)

[Try this search in The Digital Library](#)

Results 1 - 20 of 200

Result page: [1](#) [2](#) [3](#) [4](#) [5](#) [6](#) [7](#) [8](#) [9](#) [10](#) [next](#)

Best 200 shown

Relevance scale ☐ ☐ ☐ ☐ ☐

1 [Combining GAs and Symbolic Methods for High Quality Tests of Sequential Circuits](#)

Martin Keim, Nicole Drechsler, Rolf Drechsler, Bernd Becker

February 2001 **Journal of Electronic Testing: Theory and Applications**, Volume 17 Issue 1

Full text available:



[Publisher Site](#)

Additional Information: [full citation](#), [abstract](#), [index terms](#), [review](#)

A symbolic fault simulator is integrated in a Genetic Algorithm (GA) environment to perform Automatic Test Pattern Generation (ATPG) for synchronous sequential circuits. In a two phase algorithm test length and fault coverage as well are optimized. Furthermore, not only the Single Observation Time Test Strategy is supported, but also test patterns with respect to the Multiple Observation Time Test Strategy are generated. However, there are circuits that are hard to test using random patterns ...

Keywords: genetic algorithm, multiple observation time test strategy, sequential circuit ATPG, single observation time test strategy, symbolic simulation

2 [Coverage estimation for symbolic model checking](#)

Yatin Hoskote, Timothy Kam, Pei-Hsin Ho, Xudong Zhao

June 1999 **Proceedings of the 36th ACM/IEEE conference on Design automation**

Full text available:



[pdf\(79.32 KB\)](#)

Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

3 [SIVA: A System for Coverage-Directed State Space Search](#)

Malay Ganai, Praveen Yalagandula, Adnan Aziz, Andreas Kuehlmann, Vigyan Singhal

February 2001 **Journal of Electronic Testing: Theory and Applications**, Volume 17 Issue 1

Full text available:



[Publisher Site](#)

Additional Information: [full citation](#), [abstract](#), [index terms](#)

We introduce **SI**mulation **V**erification with **A**ugmentation (SIVA), a tool for coverage-directed state space search on digital hardware designs. SIVA tightly integrates simulation with symbolic techniques for efficient state space search. Specifically, the core algorithm uses a combination of ATPG and BDDs to generate "directed" input vectors, i.e., inputs which cover behavior not excited by simulation. We also present approaches to automatically generate "li ...

Keywords: coverage, formal methods, functional verification, guided search